

# MOS FIELD EFFECT TRANSISTOR 2SK3367

# SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

#### **DESCRIPTION**

The 2SK3367 is N-Channel MOS Field Effect Transistor designed for DC/DC converter application of notebook computers.

#### **FEATURES**

#### • Low on-resistance

 $R_{DS(on)1}$  = 9.0 m $\Omega$  MAX. (Vgs = 10 V, ID = 18 A)

 $R_{DS(on)2}$  = 12.0  $m\Omega$  MAX. (Vgs = 4.5 V, Ip = 18 A)

 $R_{DS(on)3} = 14.0 \text{ m}\Omega \text{ MAX.} (V_{GS} = 4.0 \text{ V}, I_{D} = 18 \text{ A})$ 

- Low C<sub>iss</sub> : C<sub>iss</sub> = 2800 pF TYP.
- Built-in gate protection diode

#### ORDERING INFORMATION

PART NUMBER	PACKAGE
2SK3367	TO-251
2SK3367-Z	TO-252

# ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Ves = 0 V)	VDSS	30	V
Gate to Source Voltage (V <sub>DS</sub> = 0 V)	Vgss	±20	V
Drain Current (DC)	I <sub>D(DC)</sub>	±36	Α
Drain Current (Pulse) Note	D(pulse)	±144	Α
Total Power Dissipation (Tc = 25 °C)	Рт	40	W
Total Power Dissipation (T <sub>A</sub> = 25 °C)	Рт	1.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to + 150	°C

**Note** PW  $\leq$  10  $\mu$ s, Duty cycle  $\leq$  1%

#### THERMAL RESISTANCE

Channel to case	Rth(ch-C)	3.13	°C/W
Channel to ambient	Rth(ch-A)	125	°C/W

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Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.



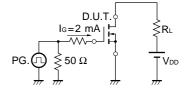
# **ELECTRICAL CHARACTERISTICS (TA = 25°C)**

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CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	RDS(on)1	V <sub>G</sub> S = 10 V, I <sub>D</sub> = 18 A		7.3	9.0	mΩ
	RDS(on)2	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 18 A		9.0	12.0	mΩ
	RDS(on)3	V <sub>GS</sub> = 4.0 V, I <sub>D</sub> = 18 A		9.7	14.0	mΩ
Gate to Source Cut-off Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	1.5	2.0	2.5	V
Forward Transfer Admittance	yfs	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 18 A	13	26		S
Drain Leakage Current	Ipss	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V			10	μΑ
Gate to Source Leakage Current	Igss	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±10	μΑ
Input Capacitance	Ciss	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz		2800		pF
Output Capacitance	Coss			880		pF
Reverse Transfer Capacitance	Crss			400		pF
Turn-on Delay Time	t <sub>d(on)</sub>	$I_D = 18 \text{ A}, V_{GS(on)} = 10 \text{ V}, V_{DD} = 15 \text{ V},$		75		ns
Rise Time	tr	$R_G = 10 \Omega$		1130		ns
Turn-off Delay Time	t <sub>d(off)</sub>			165		ns
Fall Time	t <sub>f</sub>			210		ns
Total Gate Charge	Q <sub>G</sub>	I <sub>D</sub> = 36 A, V <sub>DD</sub> = 24 V, V <sub>GS</sub> = 10 V		49		nC
Gate to Source Charge	Qgs			10		nC
Gate to Drain Charge	Q <sub>GD</sub>			14		nC
Body Diode forward Voltage	V <sub>F(S-D)</sub>	I <sub>F</sub> = 36 A, V <sub>GS</sub> = 0 V		0.95		V
Reverse Recovery Time	trr	I <sub>F</sub> = 36 A, V <sub>GS</sub> = 0 V		45		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		50		nC

# **TEST CIRCUIT 1 SWITCHING TIME**

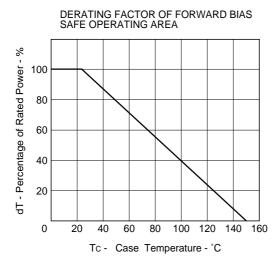
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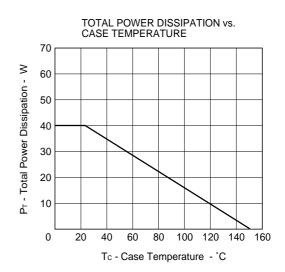
# **TEST CIRCUIT 2 GATE CHARGE**



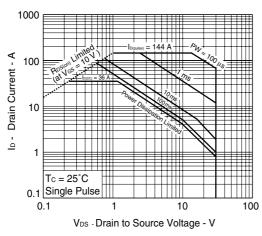


# TYPICAL CHARACTERISTICS (TA = 25°C)

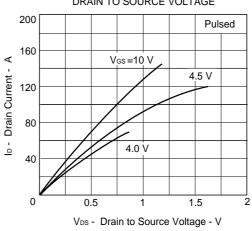




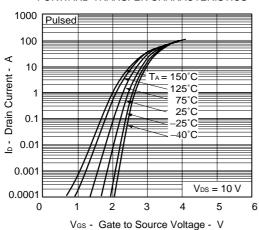
#### ★ FORWARD BIAS SAFE OPERATING AREA



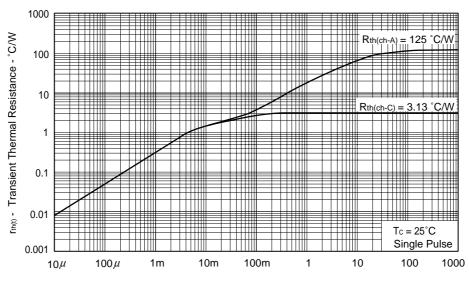




### FORWARD TRANSFER CHARACTERISTICS

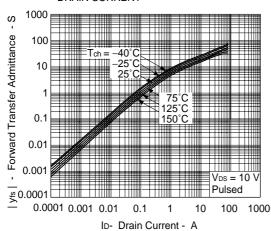


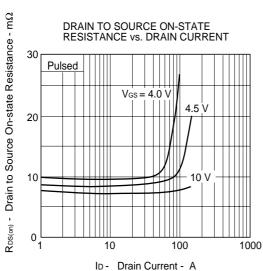
#### TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



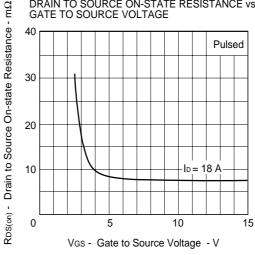
PW - Pulse Width - s



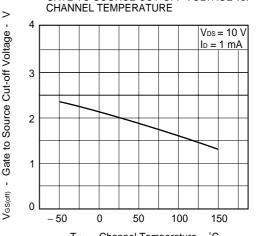




# DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

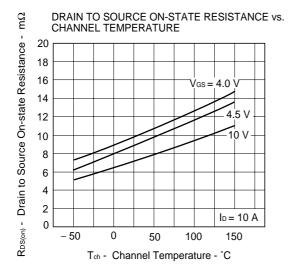


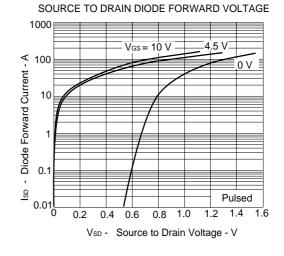
# GATE TO SOURCE CUT-OFF VOLTAGE vs.

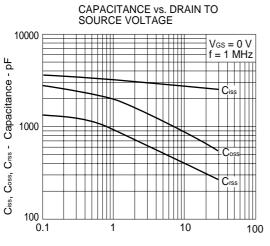


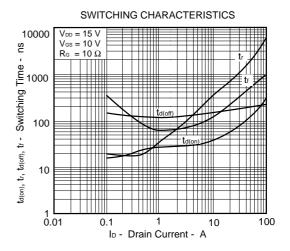
Tch - Channel Temperature - °C



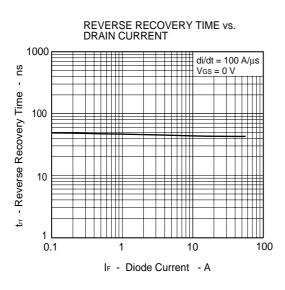


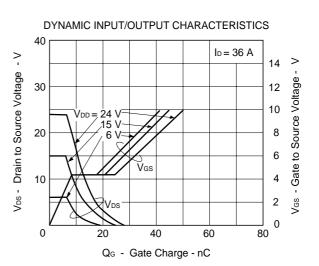










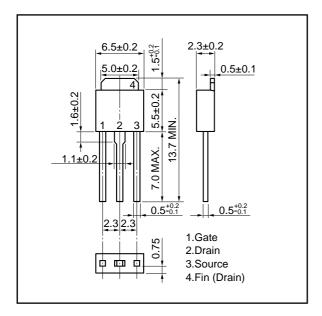


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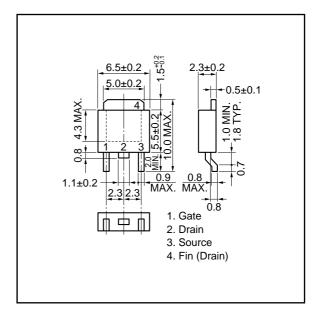


# PACKAGE DRAWINGS (Unit: mm)

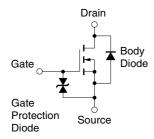
# 1) TO-251 (MP-3)



### 2) TO-252 (MP-3Z)



# **EQUIVALENT CIRCUIT**



**Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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[MEMO]

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